

# SOT-23 Plastic-Encapsulate MOSFETs

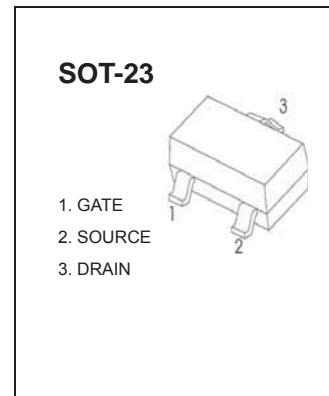
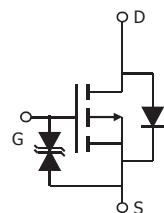
## 2SK3423 P-Channel Enhancement Mode Field Effect Transistor

### General Description

The 2SK3423 uses advanced trench technology to provide excellent RDS(ON), low gate charge and operation with gate voltages as low as 2.5V. This device is suitable for use as a load switch applications. It is ESD protected.

### Features

$V_{DS}$  (V) = -20V  
 $I_D$  = -2 A      ( $V_{GS}$  = -10V)  
 $R_{DS(ON)}$  < 92mΩ ( $V_{GS}$  = -10V)  
 $R_{DS(ON)}$  < 118mΩ ( $V_{GS}$  = -4.5V)  
 $R_{DS(ON)}$  < 166mΩ ( $V_{GS}$  = -2.5V)  
 ESD Rating: 2000V HBM



MARKING: "3423" OR "AS"

Absolute Maximum Ratings  $T_A=25^\circ\text{C}$  unless otherwise noted

Parameter	Symbol	Maximum	Units
Drain-Source Voltage	$V_{DS}$	-20	V
Gate-Source Voltage	$V_{GS}$	$\pm 12$	V
Continuous Drain Current <sup>A</sup>	$I_D$	-2	A
$T_A=70^\circ\text{C}^F$		-2	
Pulsed Drain Current <sup>B</sup>	$I_{DM}$	-8	
Power Dissipation <sup>A</sup>	$P_D$	1.4	W
$T_A=70^\circ\text{C}$		0.9	
Junction and Storage Temperature Range	$T_J, T_{STG}$	-55 to 150	°C

### Thermal Characteristics

Parameter	Symbol	Typ	Max	Units
Maximum Junction-to-Ambient <sup>A</sup>	$R_{\theta JA}$	65	90	°C/W
Steady-State		85	125	°C/W
Maximum Junction-to-Lead <sup>C</sup>	$R_{\theta JL}$	43	60	°C/W

Electrical Characteristics ( $T_J=25^\circ\text{C}$  unless otherwise noted)

Symbol	Parameter	Conditions	Min	Typ	Max	Units
<b>STATIC PARAMETERS</b>						
$\text{BV}_{\text{DSS}}$	Drain-Source Breakdown Voltage	$I_D=-250\mu\text{A}, V_{GS}=0\text{V}$	-20			V
$I_{\text{DSS}}$	Zero Gate Voltage Drain Current	$V_{DS}=-20\text{V}, V_{GS}=0\text{V}$ $T_J=55^\circ\text{C}$			-1	$\mu\text{A}$
					-5	
$I_{\text{GSS}}$	Gate-Body leakage current	$V_{DS}=0\text{V}, V_{GS}= \pm 12\text{V}$			$\pm 10$	$\mu\text{A}$
$V_{GS(\text{th})}$	Gate Threshold Voltage	$V_{DS}=V_{GS}, I_D=-250\mu\text{A}$	-0.5	-0.85	-1.2	V
$I_{D(\text{ON})}$	On state drain current	$V_{GS}=-4.5\text{V}, V_{DS}=-5\text{V}$	-17			A
$R_{DS(\text{ON})}$	Static Drain-Source On-Resistance	$V_{GS}=-10\text{V}, I_D=-2\text{A}$ $T_J=125^\circ\text{C}$		76	92	$\text{m}\Omega$
		$V_{GS}=-4.5\text{V}, I_D=-2\text{A}$		99	119	
		$V_{GS}=-2.5\text{V}, I_D=-1\text{A}$		94	118	
$R_g$	Forward Transconductance	$V_{DS}=-5\text{V}, I_D=-2\text{A}$		128	166	$\text{m}\Omega$
$V_{SD}$	Diode Forward Voltage	$I_S=-1\text{A}, V_{GS}=0\text{V}$		-0.76	-1	
$I_s$	Maximum Body-Diode Continuous Current				-1.5	A
<b>DYNAMIC PARAMETERS</b>						
$C_{iss}$	Input Capacitance	$V_{GS}=0\text{V}, V_{DS}=-10\text{V}, f=1\text{MHz}$	250	325	400	pF
$C_{oss}$	Output Capacitance		40	63	85	pF
$C_{rss}$	Reverse Transfer Capacitance		22	37	52	pF
$R_g$	Gate resistance	$V_{GS}=0\text{V}, V_{DS}=0\text{V}, f=1\text{MHz}$		11.2	17	$\Omega$
<b>SWITCHING PARAMETERS</b>						
$Q_g$	Total Gate Charge	$V_{GS}=-4.5\text{V}, V_{DS}=-10\text{V}, I_D=-2\text{A}$		3.2	4.5	nC
$Q_{gs}$	Gate Source Charge			0.6		nC
$Q_{gd}$	Gate Drain Charge			0.9		nC
$t_{D(\text{on})}$	Turn-On Delay Time	$V_{GS}=-10\text{V}, V_{DS}=-10\text{V}, R_L=5\Omega, R_{\text{GEN}}=3\Omega$		11		ns
$t_r$	Turn-On Rise Time			5.5		ns
$t_{D(\text{off})}$	Turn-Off Delay Time			22		ns
$t_f$	Turn-Off Fall Time			8		ns
$t_{rr}$	Body Diode Reverse Recovery Time	$I_F=-2\text{A}, dI/dt=100\text{A}/\mu\text{s}$		6.1		ns
$Q_{rr}$	Body Diode Reverse Recovery Charge	$I_F=-2\text{A}, dI/dt=100\text{A}/\mu\text{s}$		1.4		nC

A. The value of  $R_{\theta JA}$  is measured with the device mounted on 1in<sup>2</sup> FR-4 board with 2oz. Copper, in a still air environment with  $T_A=25^\circ\text{C}$ . The value in any given application depends on the user's specific board design.

B. The power dissipation  $P_D$  is based on  $T_{J(\text{MAX})}=150^\circ\text{C}$ , using  $\leq 10\text{s}$  junction-to-ambient thermal resistance.

C. Repetitive rating, pulse width limited by junction temperature  $T_{J(\text{MAX})}=150^\circ\text{C}$ . Ratings are based on low frequency and duty cycles to keep initial  $T_J=25^\circ\text{C}$ .

D. The  $R_{\theta JA}$  is the sum of the thermal impedance from junction to lead  $R_{\theta JL}$  and lead to ambient.

E. The static characteristics in Figures 1 to 6 are obtained using <300μs pulses, duty cycle 0.5% max.

F. These curves are based on the junction-to-ambient thermal impedance which is measured with the device mounted on 1in<sup>2</sup> FR-4 board with 2oz. Copper, assuming a maximum junction temperature of  $T_{J(\text{MAX})}=150^\circ\text{C}$ . The SOA curve provides a single pulse rating.

## Typical Characteristics

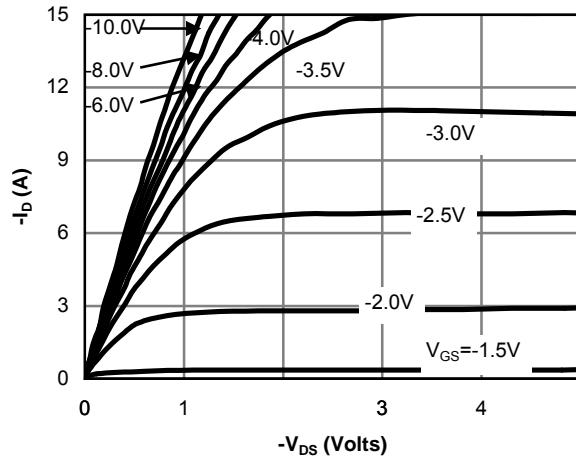


Fig 1: On-Region Characteristics

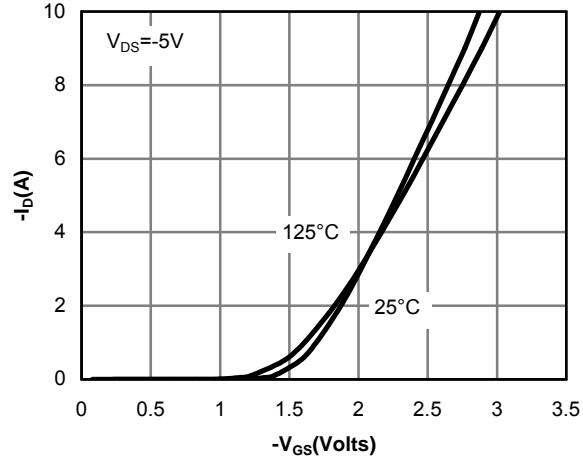


Figure 2: Transfer Characteristics

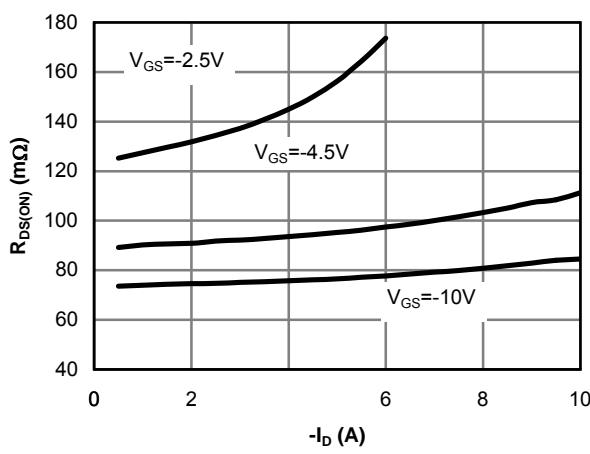


Figure 3: On-Resistance vs. Drain Current and Gate Voltage

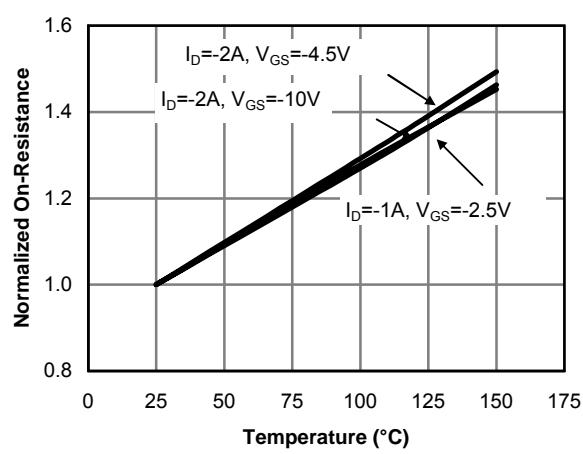


Figure 4: On-Resistance vs. Junction Temperature

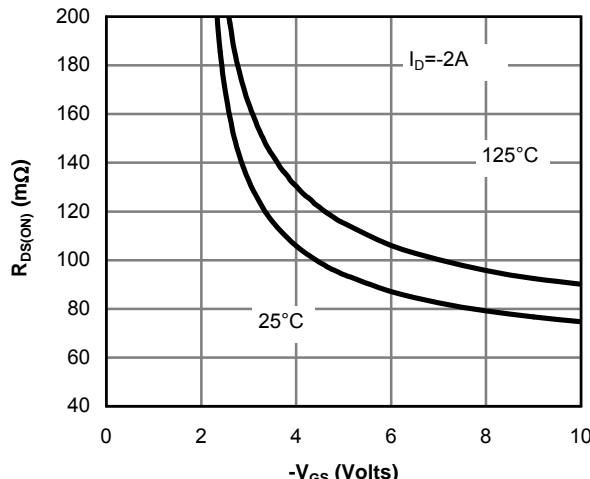


Figure 5: On-Resistance vs. Gate-Source Voltage

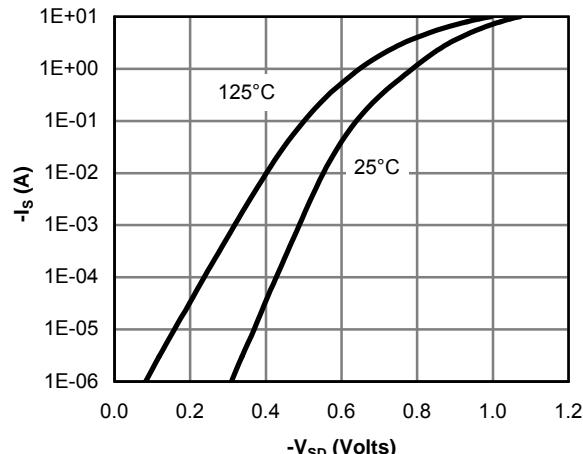


Figure 6: Body-Diode Characteristics

## Typical Characteristics

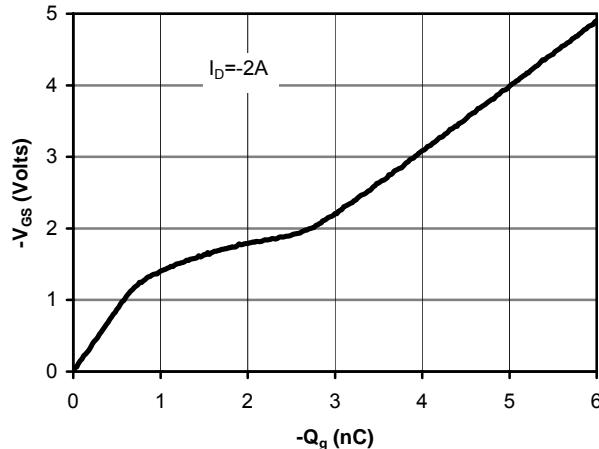


Figure 7: Gate-Charge Characteristics

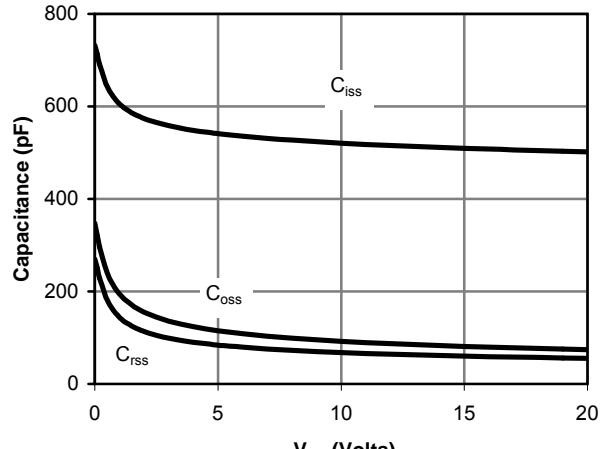


Figure 8: Capacitance Characteristics

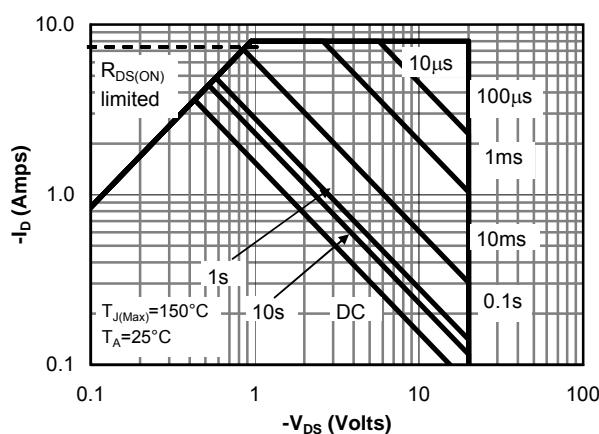


Figure 9: Maximum Forward Biased Safe Operating Area (Note E)

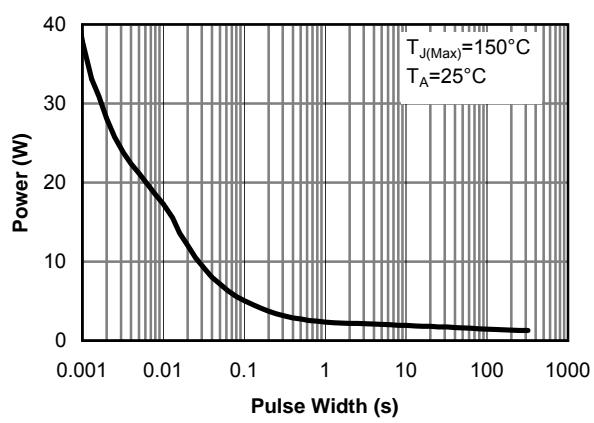


Figure 10: Single Pulse Power Rating Junction-to-Ambient (Note E)

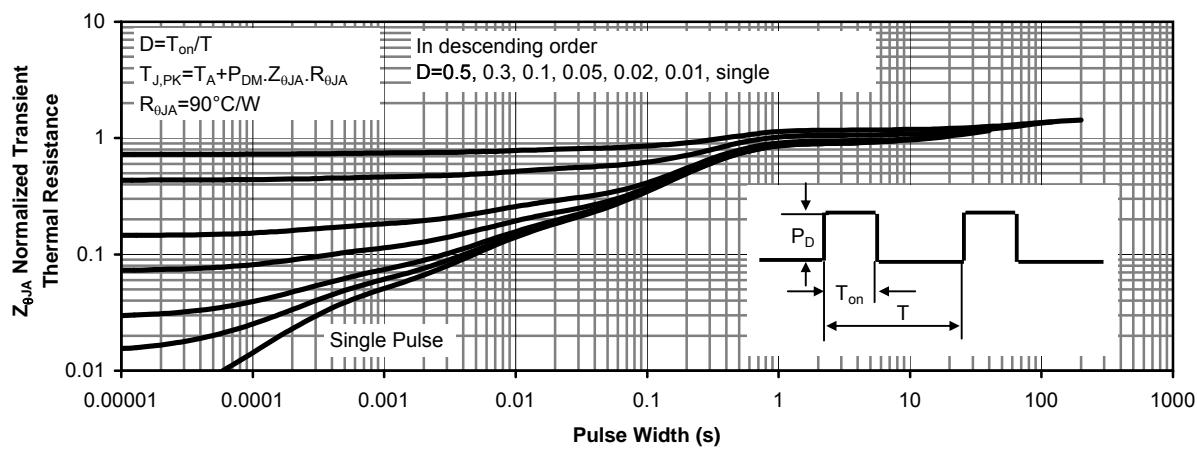
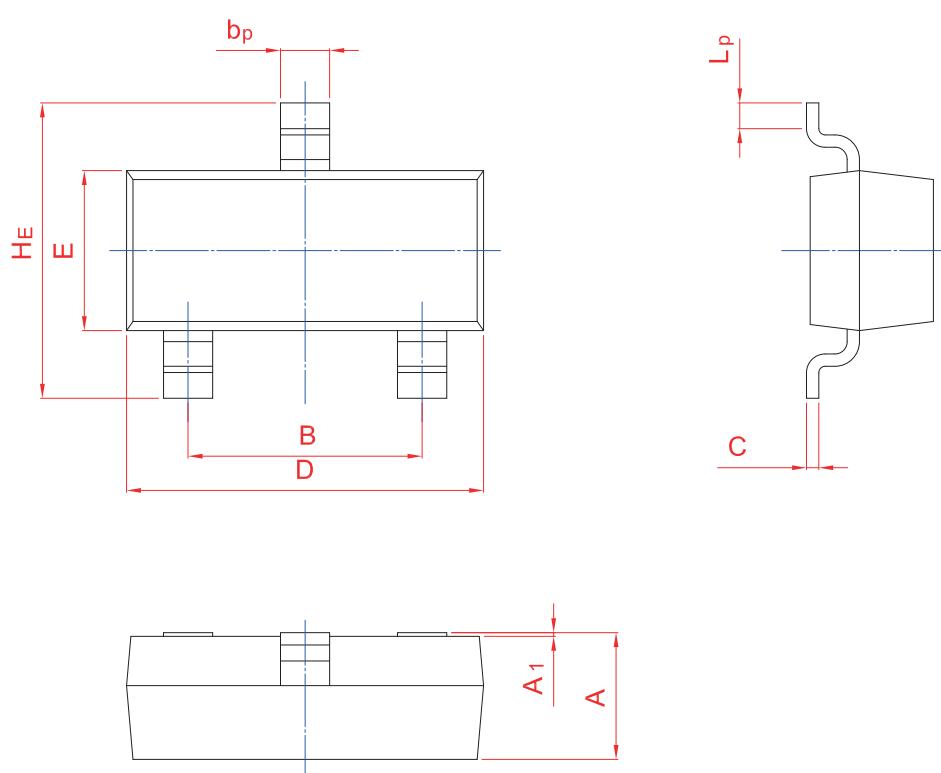


Figure 11: Normalized Maximum Transient Thermal Impedance

## PACKAGE OUTLINE

Plastic surface mounted package; 3 leads

SOT-23



UNIT	A	B	$b_p$	C	D	E	$H_E$	$A_1$	$L_p$
mm	1.40 0.95	2.04 1.78	0.50 0.35	0.19 0.08	3.10 2.70	1.65 1.20	3.00 2.20	0.100 0.013	0.50 0.20